

Title (en)

CALIBRATING DEVICE ON A SILICON SUBSTRATE

Title (de)

KALIBRIERVORRICHTUNG AUF EINEM SILIZIUMSUBSTRAT

Title (fr)

DISPOSITIF DE CALIBRATION SUR SUBSTRAT EN SILICIUM

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Application

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Abstract (en)

[origin: WO2006010821A1] The invention relates to a calibrating device on a silicon substrate SU formed in addition to reference level Nc by at least two distinct levels Ng and Nd which have two distinct dopings. Said invention also relates to a method for producing the inventive calibrating device consisting in defining at least two distinct sections Sg and Sd of the reference section Sc on a silicon substrate SU and in doping with different degrees the different sections of the reference section.

IPC 8 full level

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